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Method for measuring skin condition

Patent Assignee: IDIPS LAB CO LTD (IDIP-N)

Inventor: AHN B G; KIM Y H

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Patent Family:

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KR 2002017018	A	20020307	KR 200050072	A	20000828	200262 B

Priority Applications (No Type Date): KR 200050072 A 20000828

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
KR 2002017018	A	1	A61B-010/00	

Abstract (Basic): KR 2002017018 A

NOVELTY - Provided is a method for measuring skin condition which allows accurate general evaluation of skin by examining skin condition using differentiated condition listed according to various items and quantitatively determining skin condition dominance of items and secession from reference.

DETAILED DESCRIPTION - The method comprises(S1) a step for measuring ability to maintain moisture, (S2) a step for measuring a level of oil secretion, (S3) a step for measuring regularity of oil on skin surface, (S4) a step for measuring amount of melanin, (S5) a step for measuring a level of partial melanin deposition on skin surface, (S6) a step for measuring a pattern of corneum peeling, (S7) a step for measuring a size of skin pores, (S8) a step for measuring acnes, (S9) a step for measuring sensitivity of skin, (S10) assessing the skin condition based on the measurements of (S1) to(S9).

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Derwent Class: P31

International Patent Class (Main): A61B-010/00

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METHOD FOR MEASURING SKIN CONDITION

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Inventor(s): KIM YEONG HUN (KR); AHN BYEONG GIL (KR)
Applicant(s): IDIPS LAB CO LTD (KR)
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Equivalents:

Abstract

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